Ultra-high Fidelity Controller Hardware-in-the-Loop (cHIL) Nanosecond resolution "flight simulator" for future grid

Typhoon HIL, Inc



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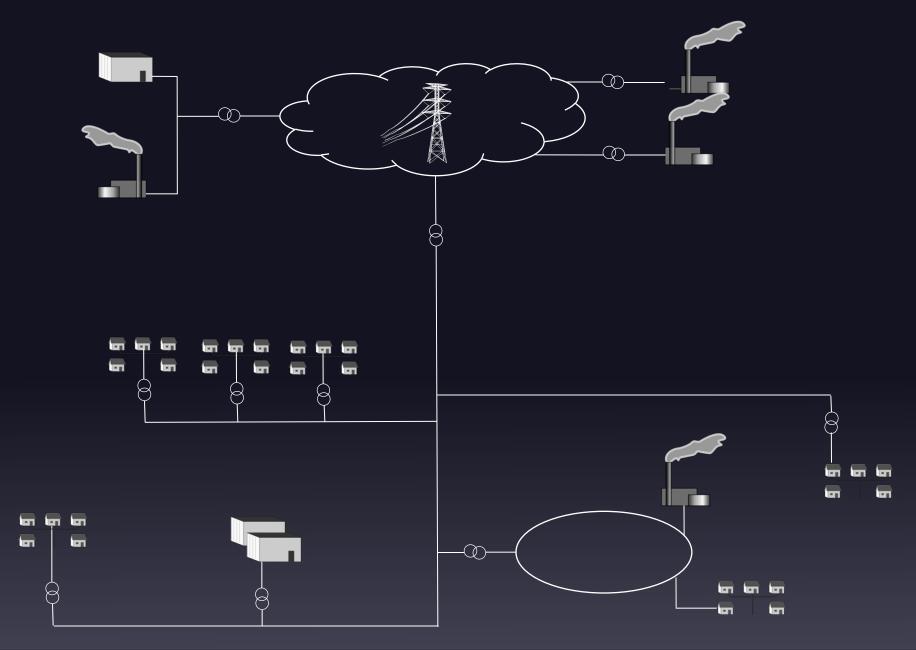
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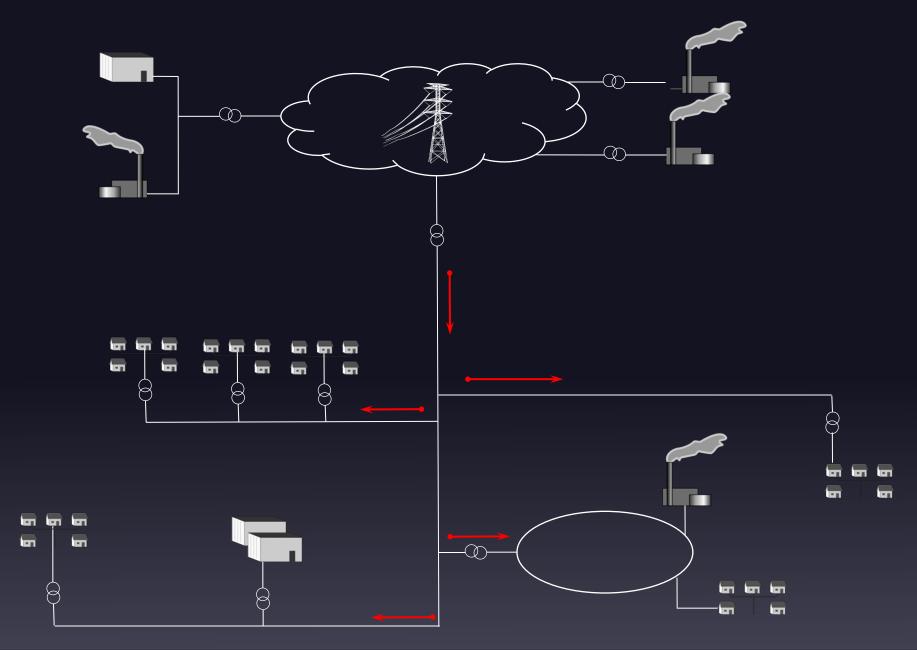
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- Real-time Controller Hardware-in-the-loop (cHIL) simulation is becoming ubiquitous in power electronics and power systems

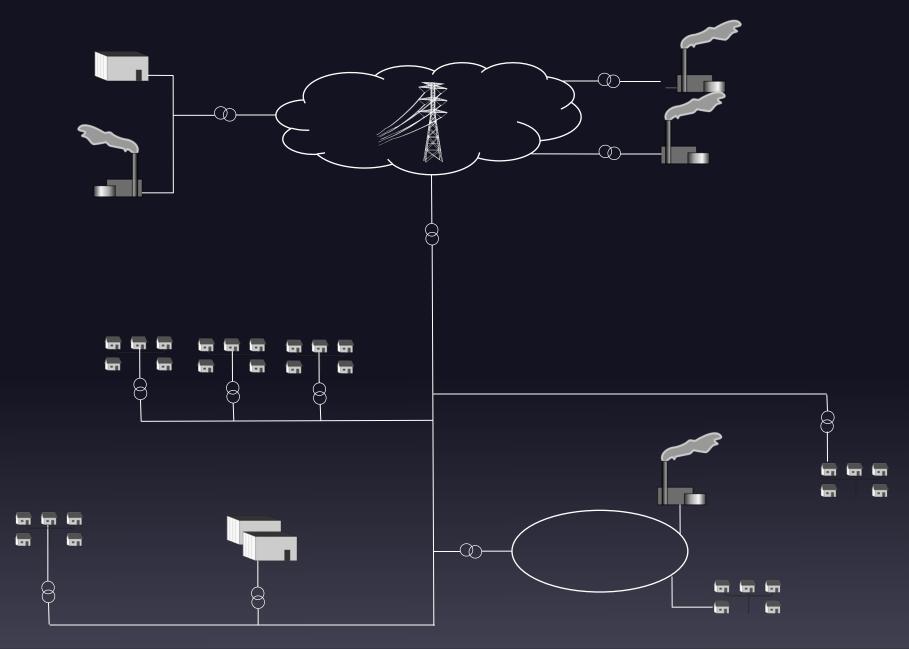
Standard picture of the power grid

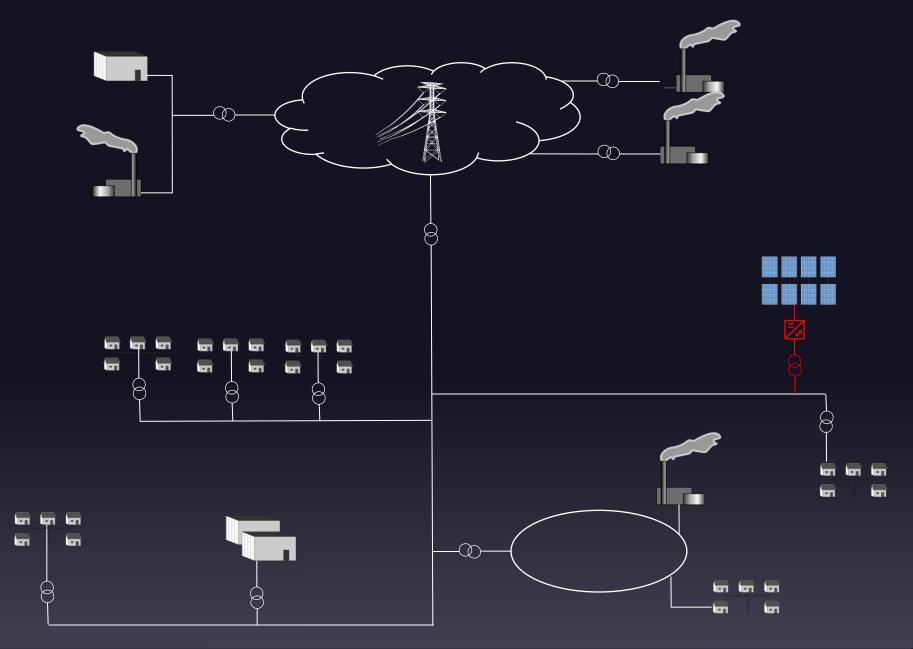
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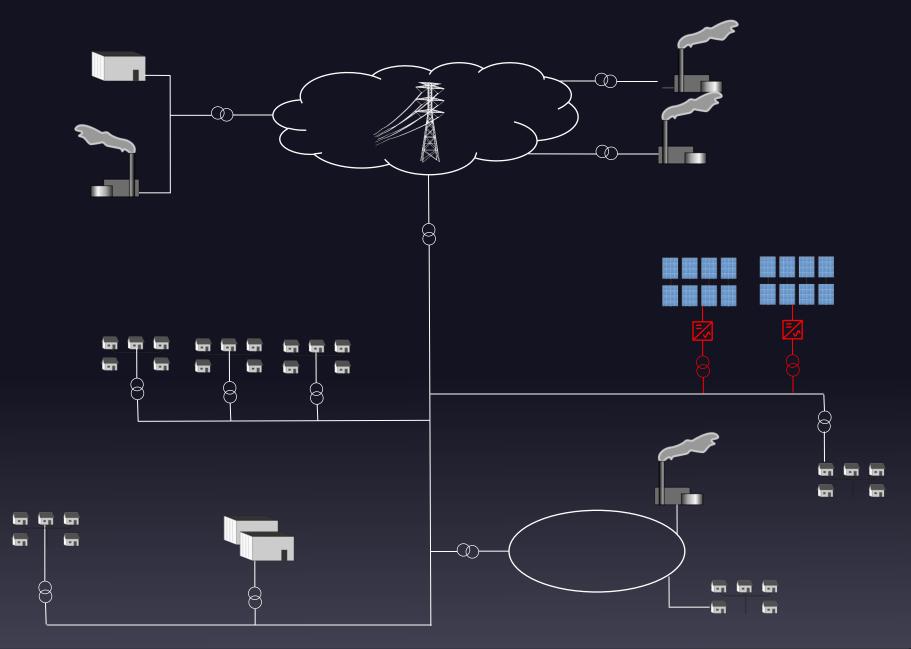


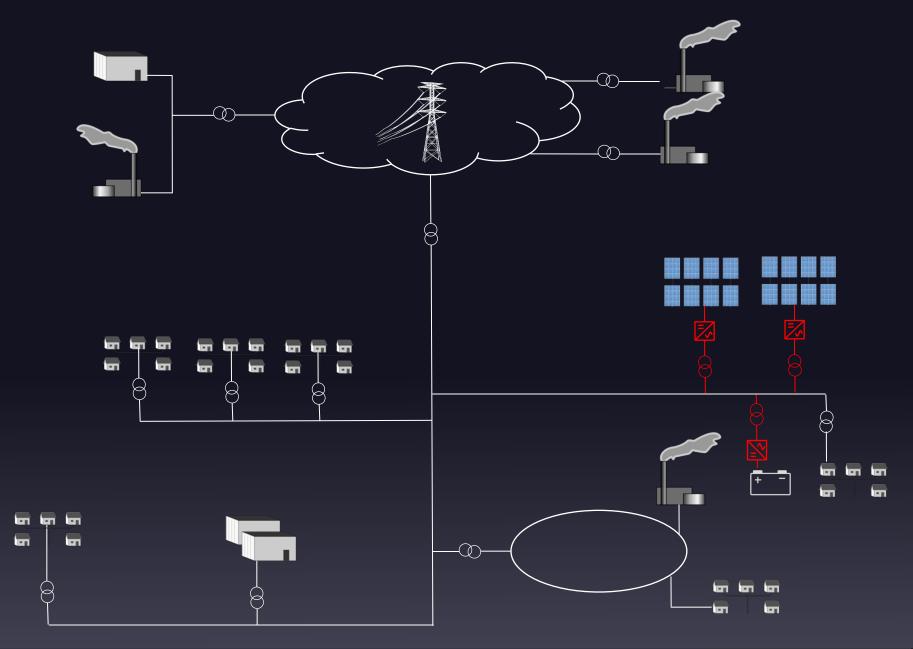
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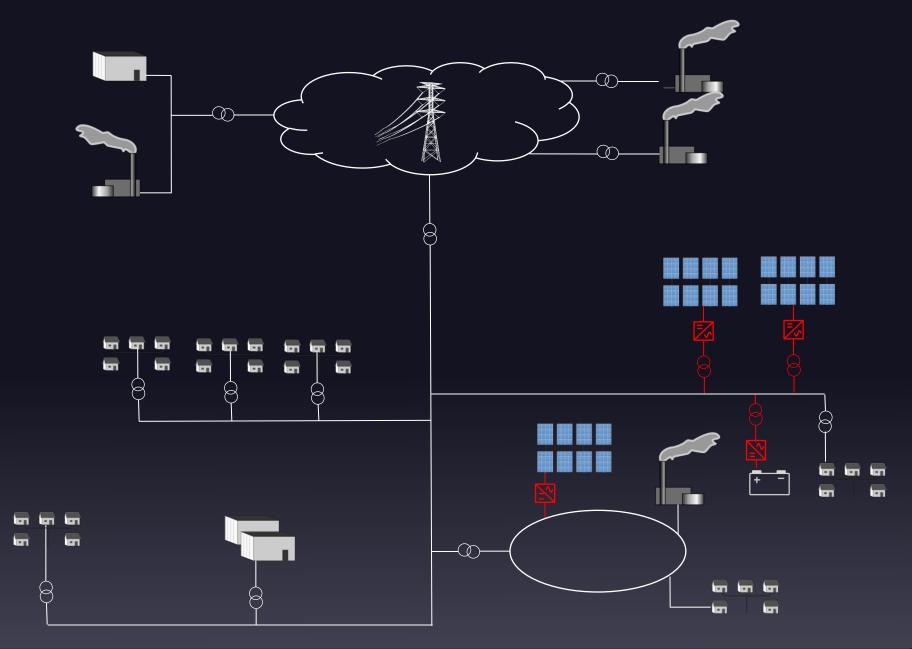


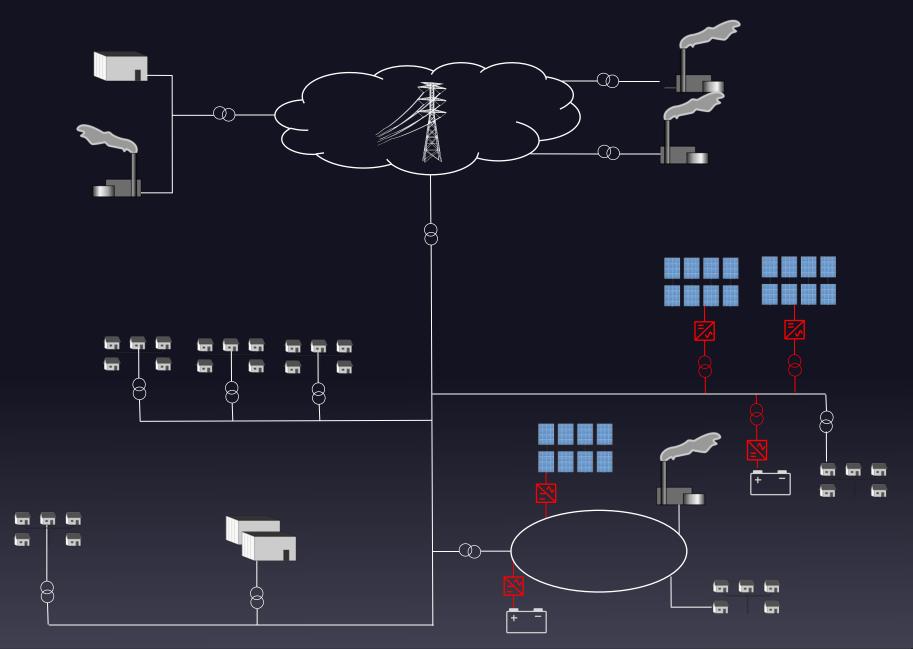


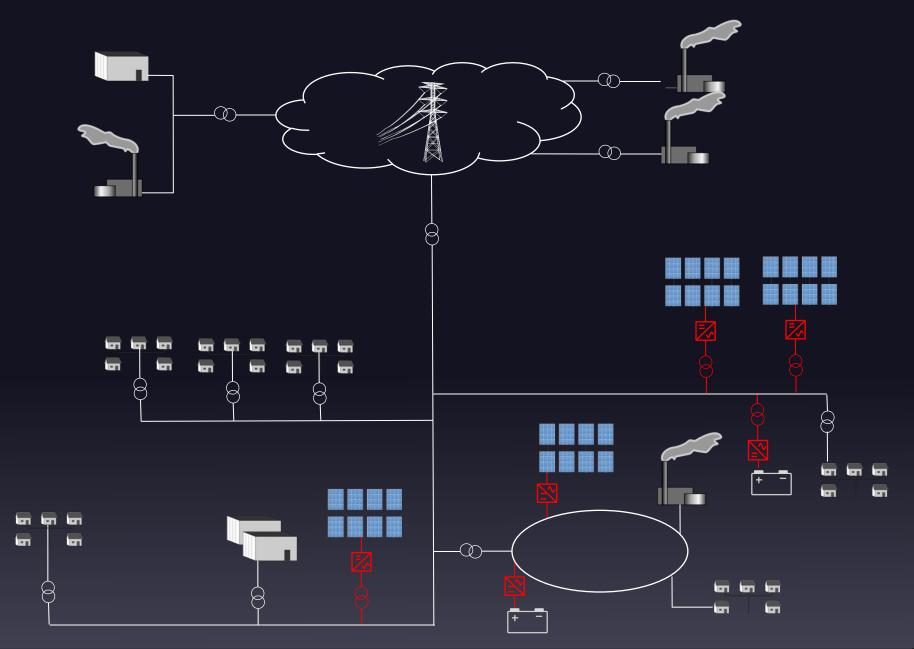


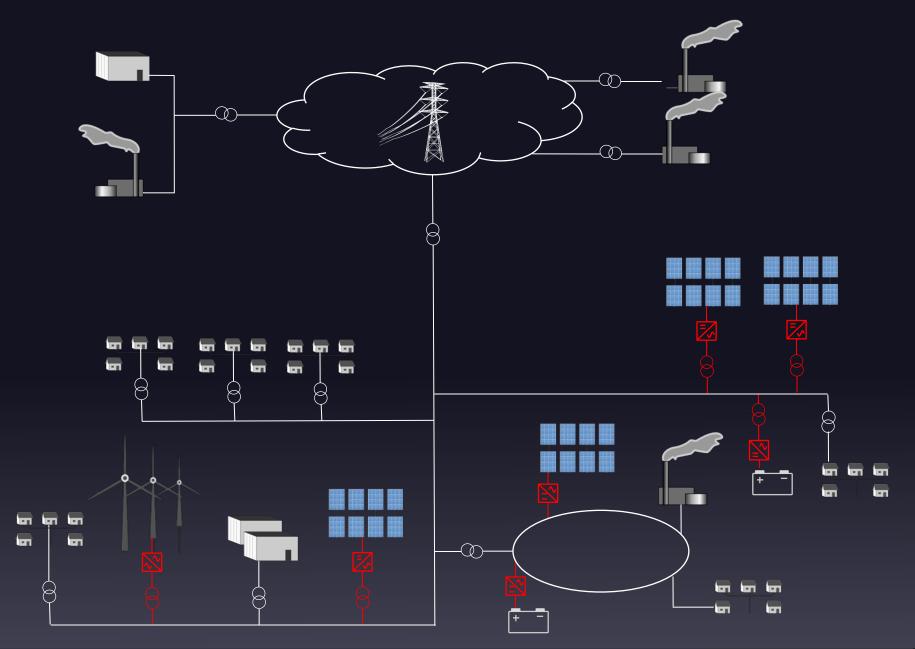


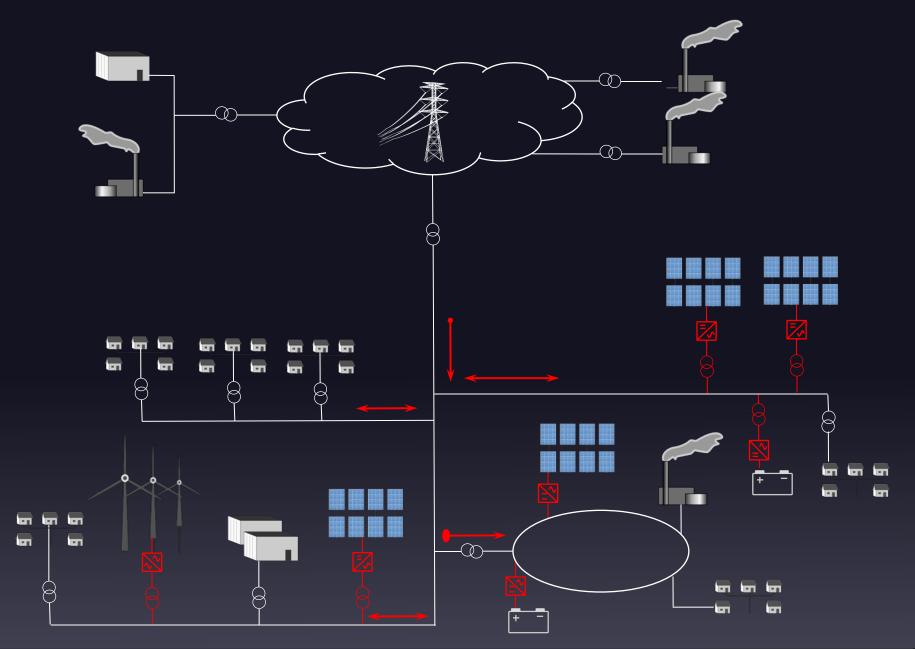


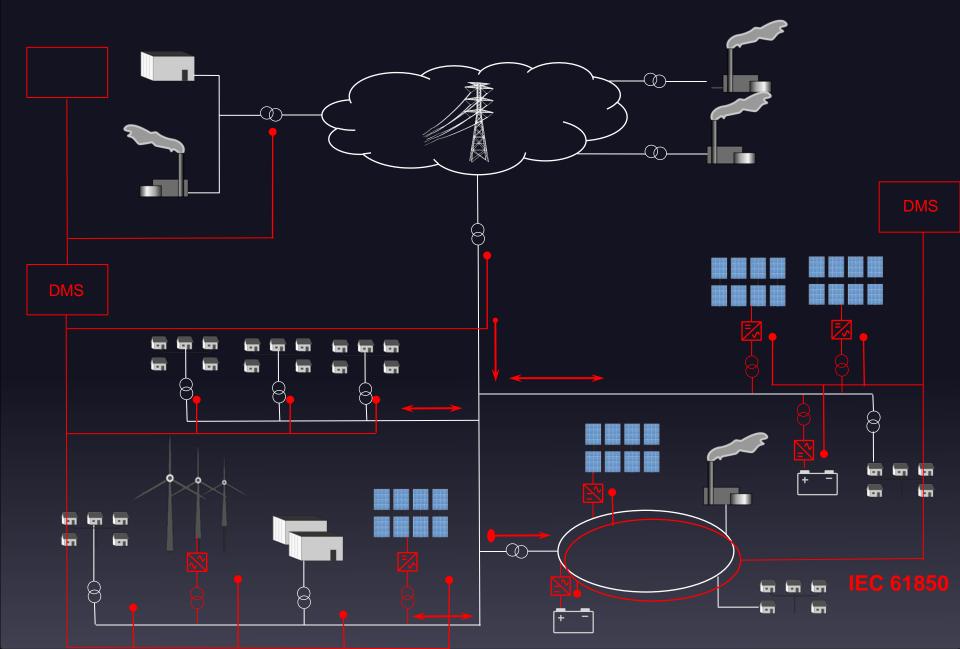




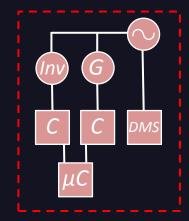




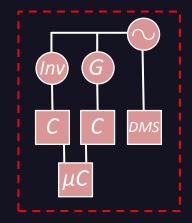




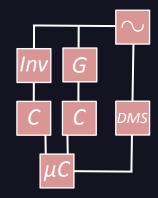
Simulation



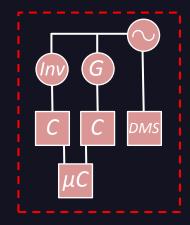
Simulation



Complete System

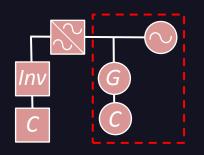


Simulation



Power HIL

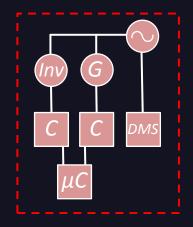
Complete System



Inv G C C DMS μC

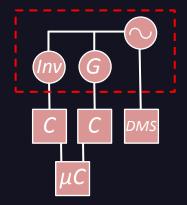
Inv

C



Simulation

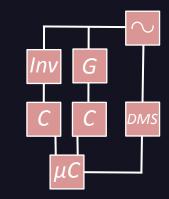
Controller HIL

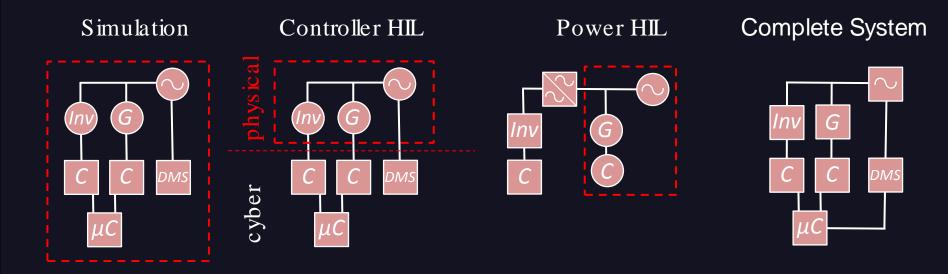


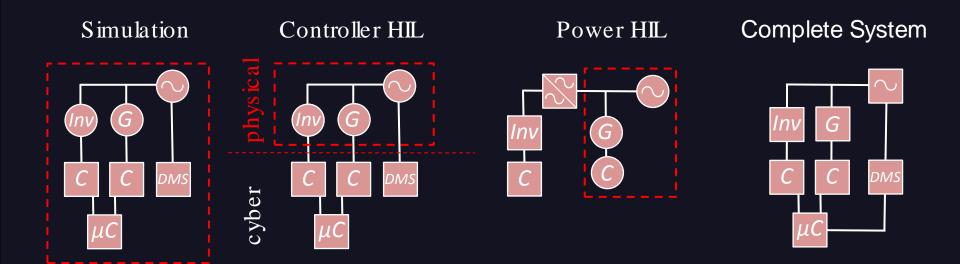
Power HIL

G

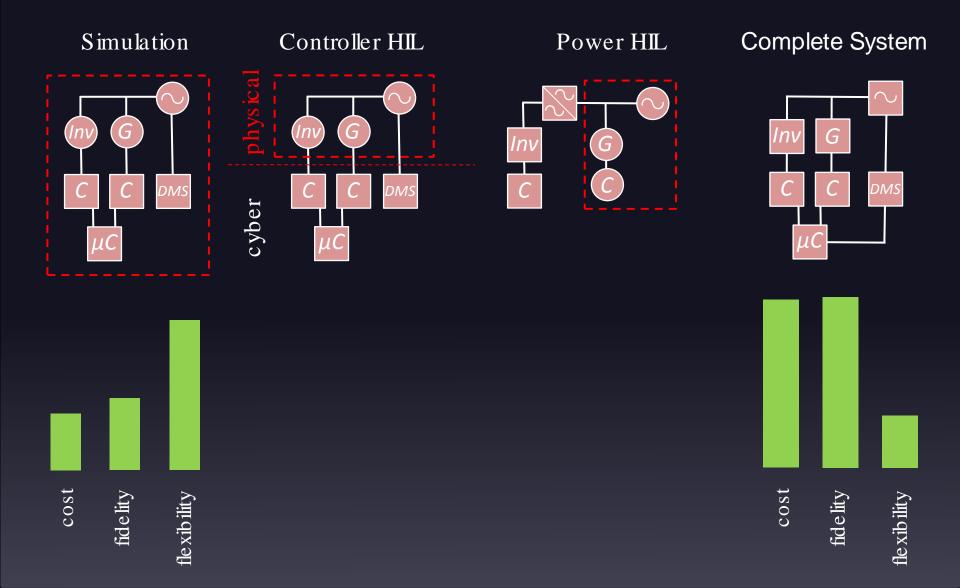
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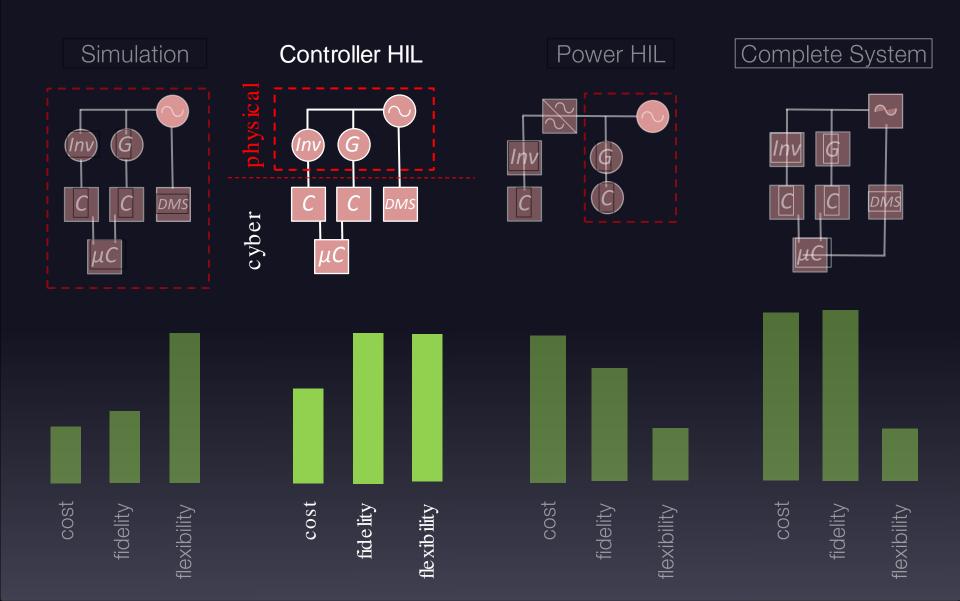




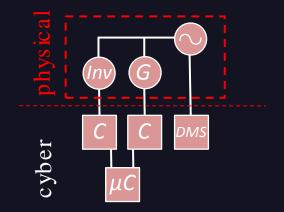






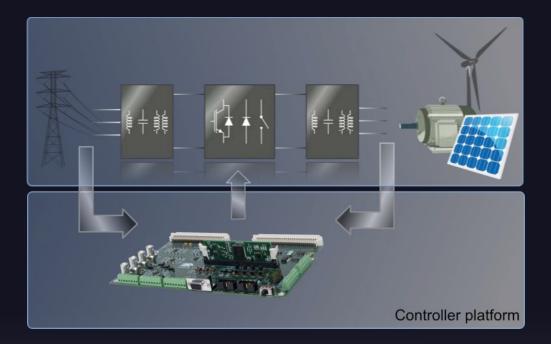


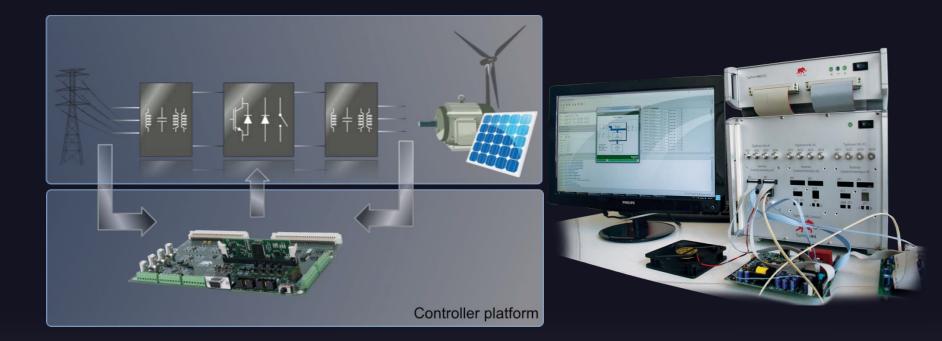
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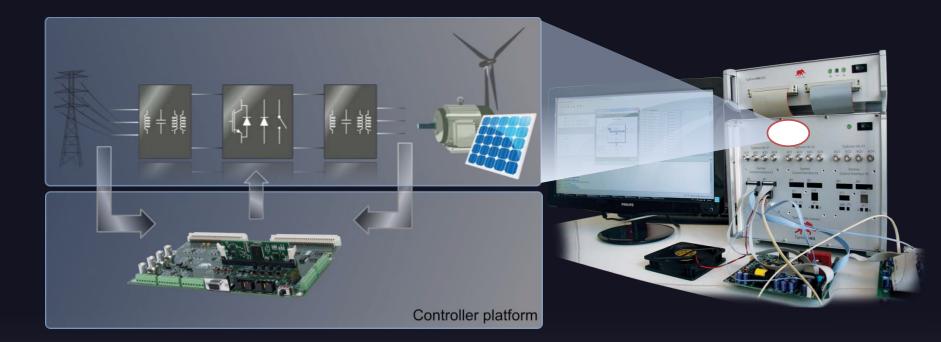


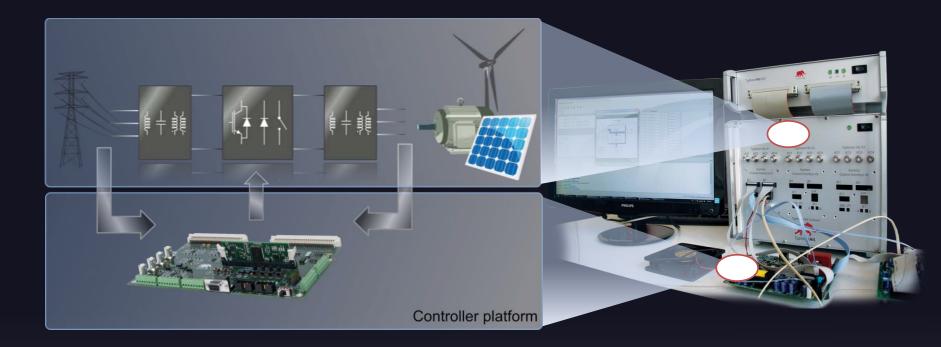


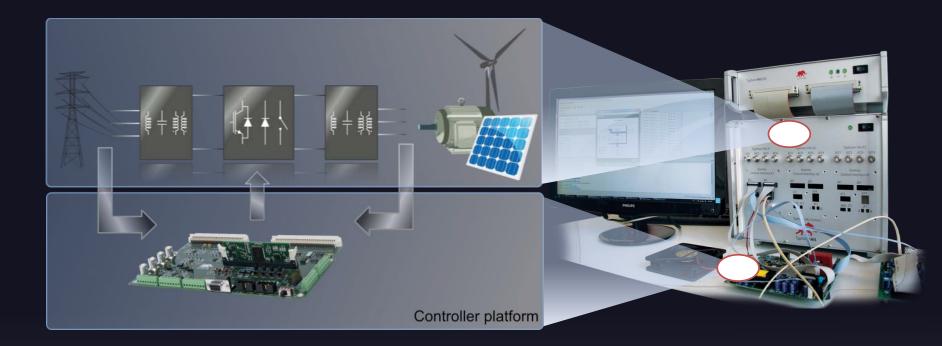








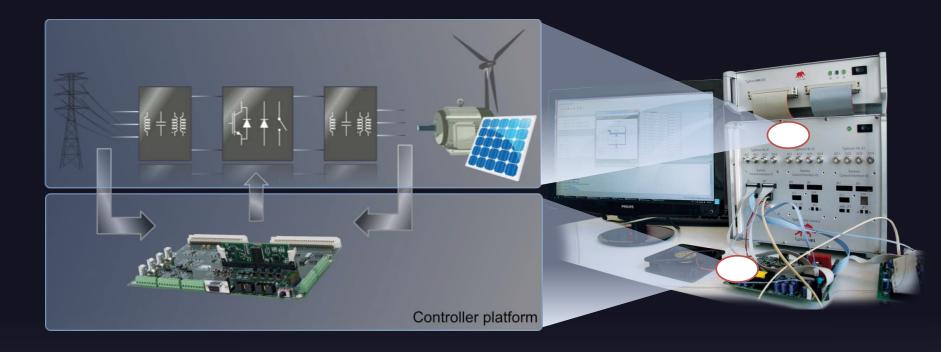






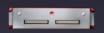


Power electronics product lifecycle

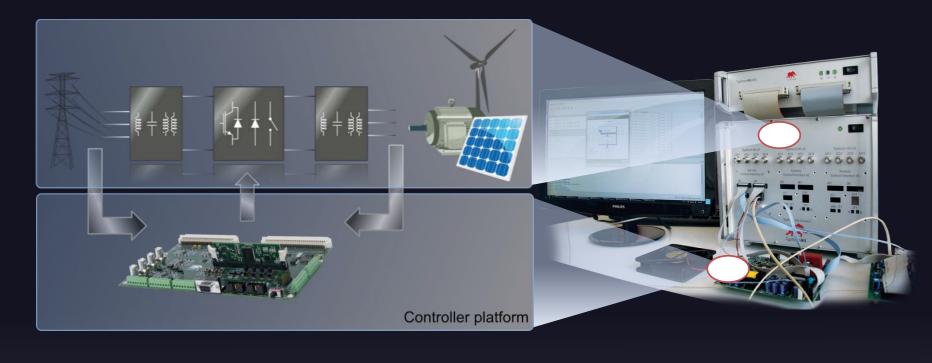


R&D Development





Power electronics product lifecycle

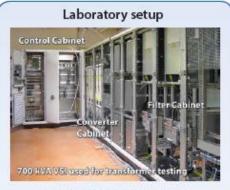


 R&D
 Development
 Converter Testing

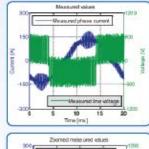
 Image: Second second

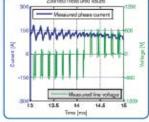
Power electronics product lifecycle

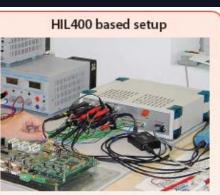
Ultra-high fidelity: 20 ns PWM sampling, 0.5-1µs time step



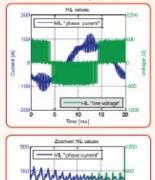
Laboratory setup results

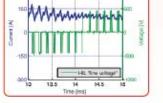






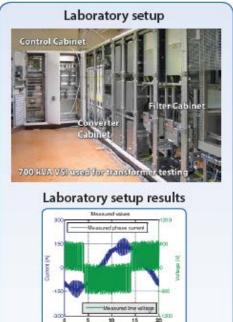
HIL400 setup results

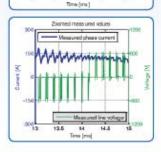




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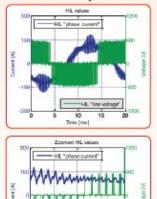
Easy to use







HIL400 setup results

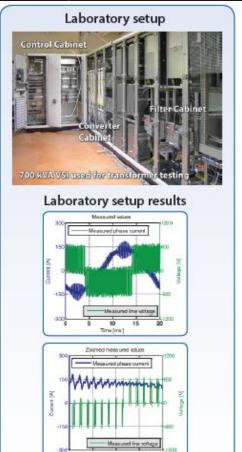


12.5



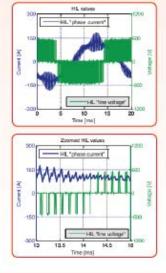
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HIL400 setup results

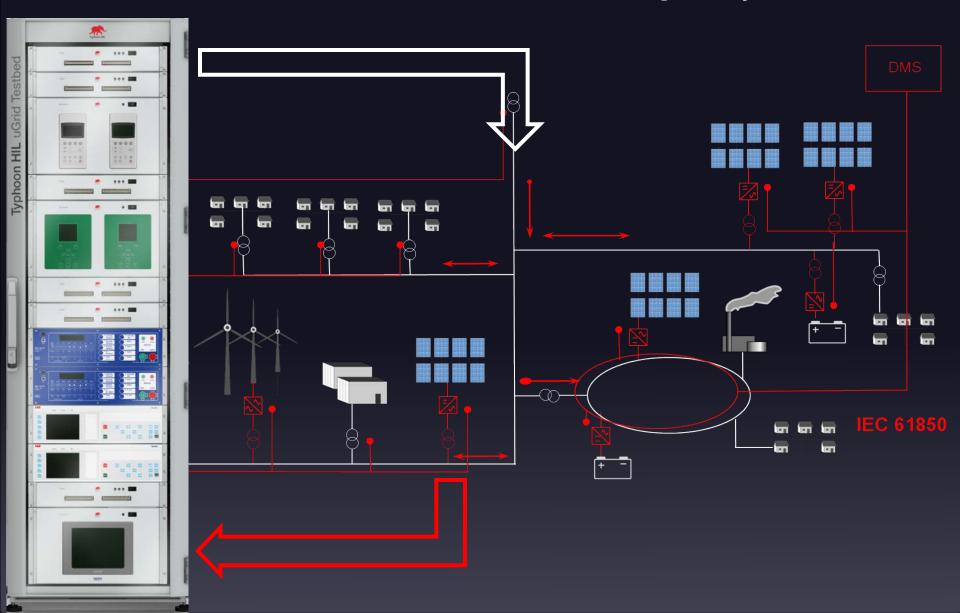


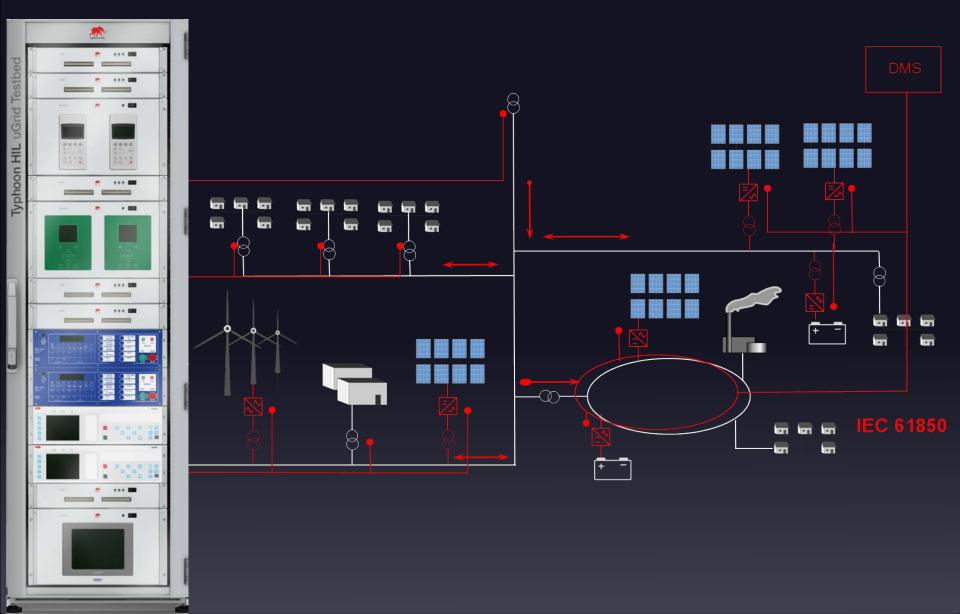


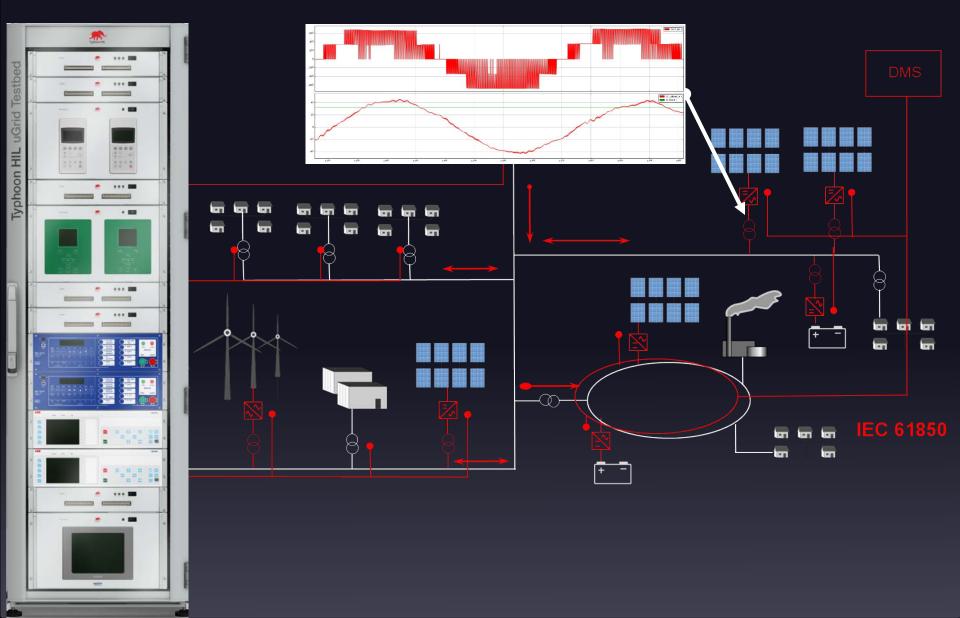
Plug and play interface to industrial controllers (customized)

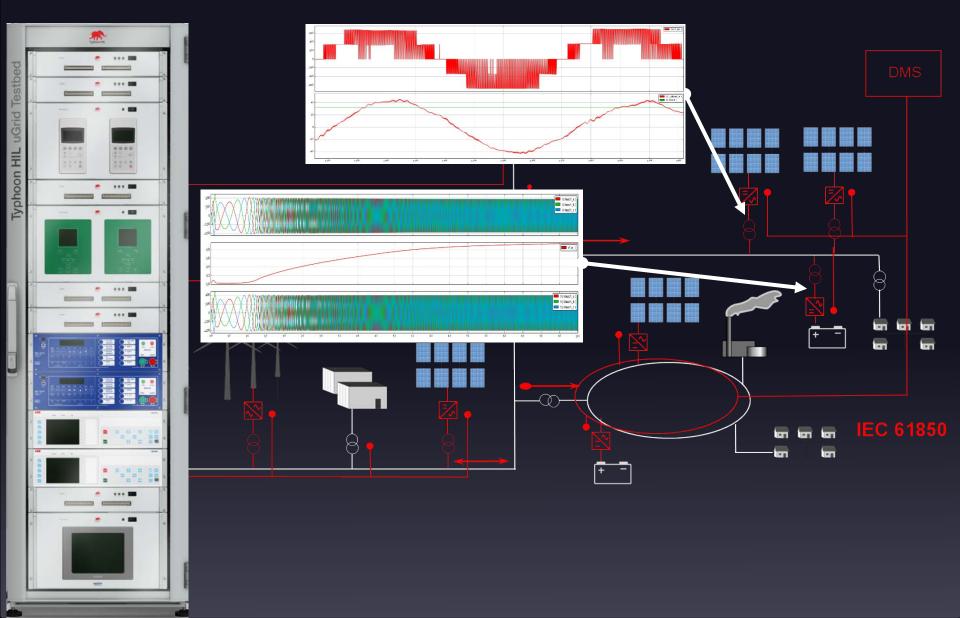


The new way of **TESTING Complete Systems**. The **Controller Hardware-in-the-Loop** way.











Ultra-high fidelity via vertically integrated cHIL solution

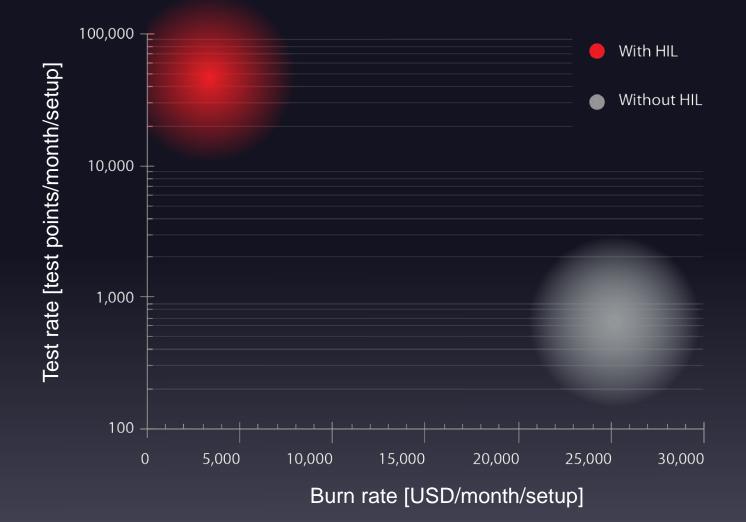


Typhoon HIL Solution

OEM Control System

cHIL Advantage: orders of magnitude better test coverage orders of magnitude lower cost of testing

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- Poor software quality has become one of the most expensive topics in human history: > \$150 billion per year in U.S.
- Improving software quality is a key topic for all industries. Power systems included.

Differential analyzer, Vannevar Bush, MIT 1927





Test relentlesly.

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